60V N+P-Channel Enhancement Mode MOSFET

RoHS COMPLIANT

GENERAL DESCRIPTION

The XPX603DFX HE uses advanced trench technology MOSFETs to provide excellent RDS(ON) and low gate charge. The complementary MOSFETs may be used to form a level shifted high side switch, and for a host of other applications. Standard Product XPX603DFX is Pb-free. XPX603DFX is electrically identical.

GENERAL FEATURES

- High density cell design for ultra low Rdson
- Fully characterized avalanche voltage and current
- Good stability and uniformity with high EAS
- Excellent package for good heat dissipation
- Special process technology for high ESD capability

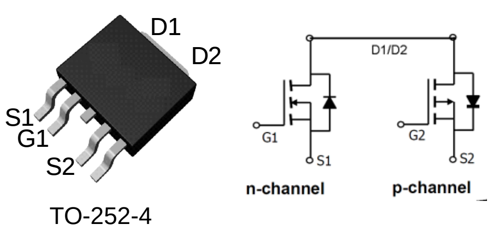
N-channel

- V_{DS} =60V, I_D =23A
  $R_{DS(ON)}$ =25mΩ @ V_{GS}=10V
  $R_{DS(ON)}$ =32mΩ @ V_{GS}=4.5V

P-channel

- VDS =-60V,ID =-18A
  RDS(ON) =55mΩ @ VGS=-10V
  RDS(ON) =75 mΩ @ VGS=-4.5V

PIN CONFIGURATION



Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
XPX603DFX	TO-252-4	XPX603DFX XXXX YYYY	2500

Absolute Maximum Ratings (T_A = 25°C unless otherwise noted)

Symbol	Parameter	Rating		Units
		N-Channel	P-Channel	
V_{DS}	Drain-Source Voltage	60	-60	V
V_{GS}	Gate-Source Voltage	±20	±20	V
I_D@T_C=25˚C	Continuous Drain Current, V_{GS} @ 10V[1]	23	-18	A
I_D@T_C=100˚C	Continuous Drain Current, V_{GS} @ 10V[1]	15	-11	A
I_D@T_A=25˚C	Continuous Drain Current, V_{GS} @ 10V[1]	5.6	-4.3	A
I_D@T_A=70˚C	Continuous Drain Current, V_{GS} @ 10V[1]	4.5	-3.5	A
I_{DM}	Pulsed Drain Current[2]	46	-36	A
EAS	Single Pulse Avalanche Energy[3]	34.5	51.2	mJ
I_{AS}	Avalanche Current	22.6	-26.6	A
P_D@T_C=25˚C	Total Power Dissipation[4]	34.7	34.7	W
P_D@T_A=25˚C	Total Power Dissipation[4]	2	2	W
T_{STG}	Storage Temperature Range	-55 to 150	-55 to 150	˚C
T_J	Operating Junction Temperature Range	-55 to 150	-55 to 150	˚C
$R_{θJA}$	Thermal Resistance Junction-Ambient [1]	---	62	˚C/W
$R_{θJC}$	Thermal Resistance Junction-Case[1]	---	3.6	˚C/W

Electrical Characteristics (T_C=25℃unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
BV_{DSS}	Drain-Source Breakdown Voltage	V_{GS}=0V , I_D=250uA	60	---	---	V
$\triangle BV_{DSS}/\triangle T_J$	BV_{DSS} Temperature Coefficient	Reference to 25˚C , I_D=1mA	---	0.063	---	V/˚C
$R_{DS(ON)}$	Static Drain-Source On-Resistance[2]	V_{GS}=10V , I_D=15A	---	25	32	mΩ
		V_{GS}=4.5V , I_D=10A	---	32	38	
$V_{GS(th)}$	Gate Threshold Voltage	V_{GS}=V_{DS} , I_D =250uA	1.2	---	2.5	V
$\triangle V_{GS(th)}$	$V_{GS(th)}$ Temperature Coefficient		---	-5.24	---	mV/˚C
I_{DSS}	Drain-Source Leakage Current	V_{DS}=48V , V_{GS}=0V , T_J=25˚C	---	---	1	uA
		V_{DS}=48V , V_{GS}=0V , T_J=55˚C	---	---	5	
I_{GSS}	Gate-Source Leakage Current	V_{GS}=±20V , V_{DS}=0V	---	---	±100	nA
gfs	Forward Transconductance	V_{DS}=5V , I_D=15A	---	17	---	S
R_g	Gate Resistance	V_{DS}=0V , V_{GS}=0V , f=1MHz	---	3.2	---	
Q_g	Total Gate Charge (4.5V)	V_{DS}=48V , V_{GS}=4.5V , I_D=12A	---	12.56	---	nC
Q_{gs}	Gate-Source Charge		---	3.24	---	
Q_{gd}	Gate-Drain Charge		---	6.31	---	
$T_{d(on)}$	Turn-On Delay Time	V_{DD}=30V , V_{GS}=10V , R_G=3.3 , I_D=10A	---	8	---	ns
T_r	Rise Time		---	14.2	---	
$T_{d(off)}$	Turn-Off Delay Time		---	24.4	---	
T_f	Fall Time		---	4.6	---	
C_{iss}	Input Capacitance	V_{DS}=15V , V_{GS}=0V , f=1MHz	---	1378	---	pF
C_{oss}	Output Capacitance		---	86	---	
C_{rss}	Reverse Transfer Capacitance		---	64	---	
I_S	Continuous Source Current[1,5]	V_G=V_D=0V , Force Current	---	---	23	A
I_{SM}	Pulsed Source Current[2,5]		---	---	46	A
V_{SD}	Diode Forward Voltage[2]	V_{GS}=0V , I_S=1A , T_J=25˚C	---	---	1.2	V

Note :

1.The data tested by surface mounted on a 1 inch ^{2} FR-4 board with 2OZ copper.

2.The data tested by pulsed , pulse width ≦300us , duty cycle ≦2%

3.The EAS data shows Max. rating . The test condition is V^{DD}=25V,V^{GS}=10V,L=0.1mH,I^{AS}=22.6A

4.The power dissipation is limited by 150˚C junction temperature

5 .The data is theoretically the same as I_D and I_{DM} , in real applications , should be limited by total power dissipation.

P-Channel Electrical Characteristics (T_J=25 ℃, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
BV_{DSS}	Drain-Source Breakdown Voltage	V_{GS}=0V , I_D=-250uA	-60	---	---	V
$\triangle BV_{DSS}/\triangle T_J$	BV_{DSS} Temperature Coefficient	Reference to 25℃ , I_D=-1mA	---	-0.03	---	V/℃
$R_{DS(ON)}$	Static Drain-Source On-Resistance[2]	V_{GS}=-10V , I_D=-12A	---	55	70	mΩ
		V_{GS}=-4.5V , I_D=-8A	---	75	105	
$V_{GS(th)}$	Gate Threshold Voltage	V_{GS}=V_{DS} , I_D =-250uA	-1.2	---	-2.5	V
$\triangle V_{GS(th)}$	$V_{GS(th)}$ Temperature Coefficient		---	4.56	---	mV/℃
I_{DSS}	Drain-Source Leakage Current	V_{DS}=-48V , V_{GS}=0V , T_J=25℃	---	---	1	uA
		V_{DS}=-48V , V_{GS}=0V , T_J=55℃	---	---	5	
I_{GSS}	Gate-Source Leakage Current	V_{GS}=±20V , V_{DS}=0V	---	---	±100	nA
gfs	Forward Transconductance	V_{DS}=-5V , I_D=-12A	---	15	---	S
R_g	Gate Resistance	V_{DS}=0V , V_{GS}=0V , f=1MHz	---	13.5	---	Ω
Q_g	Total Gate Charge (-4.5V)	V_{DS}=-48V , V_{GS}=-4.5V , I_D=-12A	---	9.86	---	nC
Q_{gs}	Gate-Source Charge		---	3.08	---	
Q_{gd}	Gate-Drain Charge		---	2.95	---	
$T_{d(on)}$	Turn-On Delay Time	V_{DD}=-15V , V_{GS}=-10V , R_G=3.3 , I_D=-1A	---	28.8	---	ns
T_r	Rise Time		---	19.8	---	
$T_{d(off)}$	Turn-Off Delay Time		---	60.8	---	
T_f	Fall Time		---	7.2	---	
C_{iss}	Input Capacitance	V_{DS}=-15V , V_{GS}=0V , f=1MHz	---	1447	---	pF
C_{oss}	Output Capacitance		---	97	---	
C_{rss}	Reverse Transfer Capacitance		---	70	---	
I_S	Continuous Source Current[1,5]	V_G=V_D=0V , Force Current	---	---	-18	A
I_{SM}	Pulsed Source Current[2,5]		---	---	-36	A
V_{SD}	Diode Forward Voltage[2]	V_{GS}=0V , I_S=-1A , T_J=25℃	---	---	-1.2	V

Note :

1.The data tested by surface mounted on a 1 inch ^{2} FR-4 board with 2OZ copper.

2.The data tested by pulsed , pulse width ≦ 300us , duty cycle ≦ 2%

3.The EAS data shows Max. rating . The test condition is V^{DD}=-25V,V^{GS}=-10V,L=0.1mH,I^{AS}=-26.6A

4.The power dissipation is limited by 150℃ junction temperature

5 .The data is theoretically the same as I_D and I_{DM} , in real applications , should be limited by total power dissipation.

N-Channel Typical Characteristics

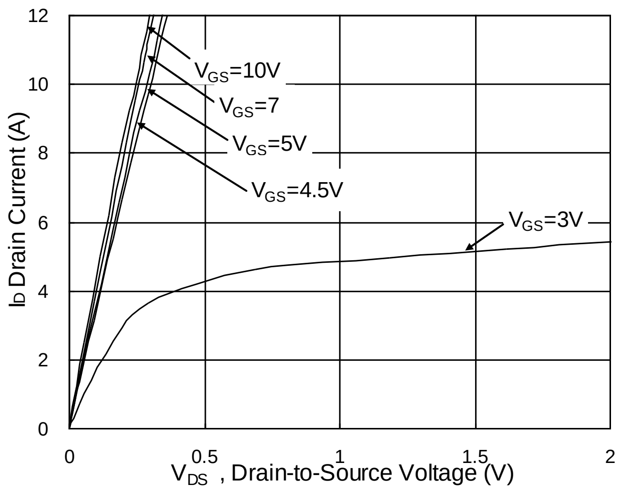


Fig.1 Typical Output Characteristics

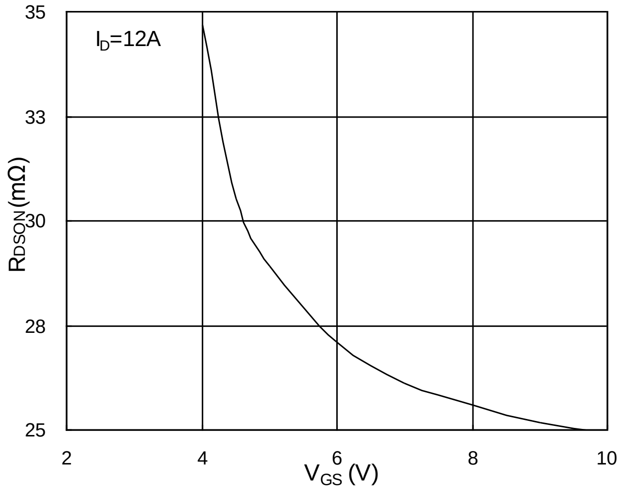


Fig.2 On-Resistance v.s Gate-Source

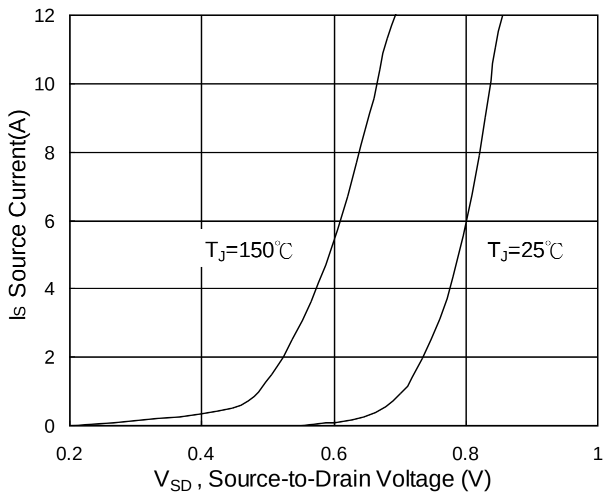


Fig.3 Forward Characteristics of Reverse

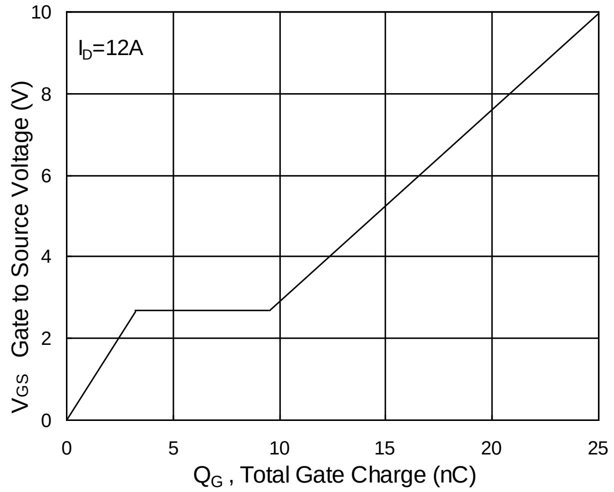


Fig.4 Gate-Charge Characteristics

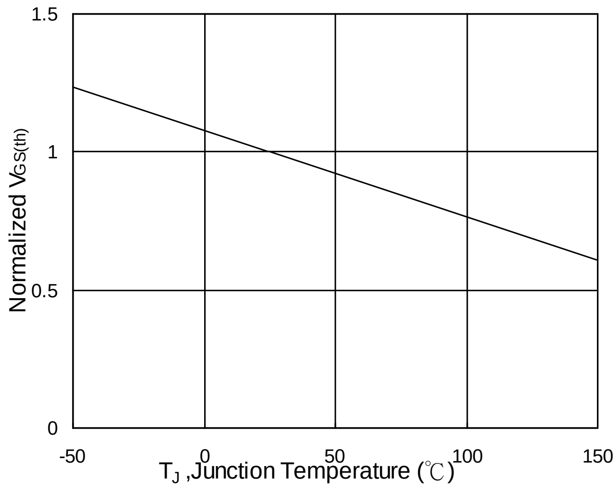


Fig.5 Normalized $V_{GS(th)}$ v.s T_J

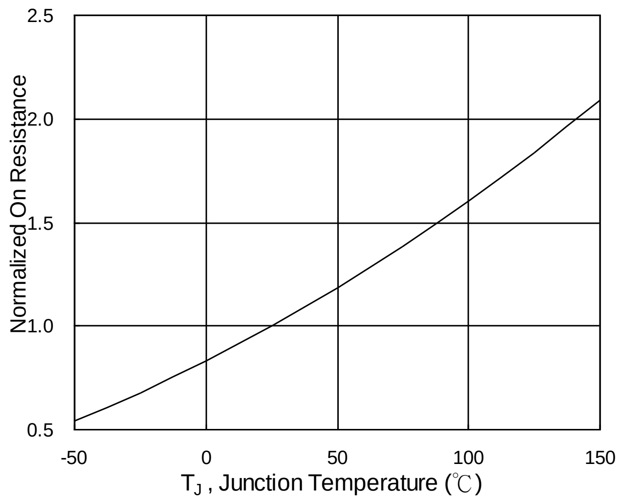


Fig.6 Normalized R_{DSON} v.s T_J

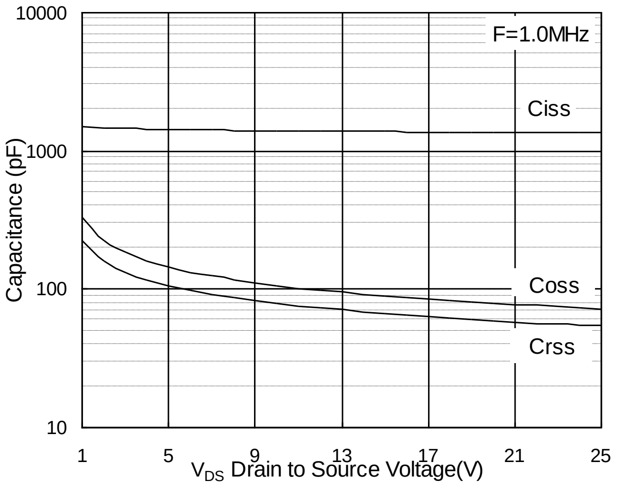


Fig.7 Capacitance

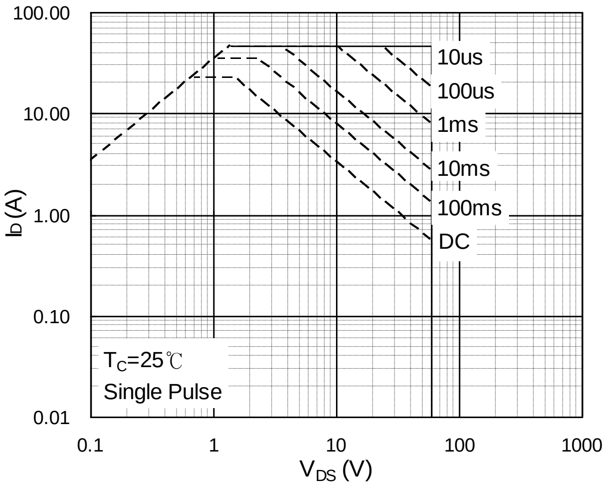


Fig.8 Safe Operating Area

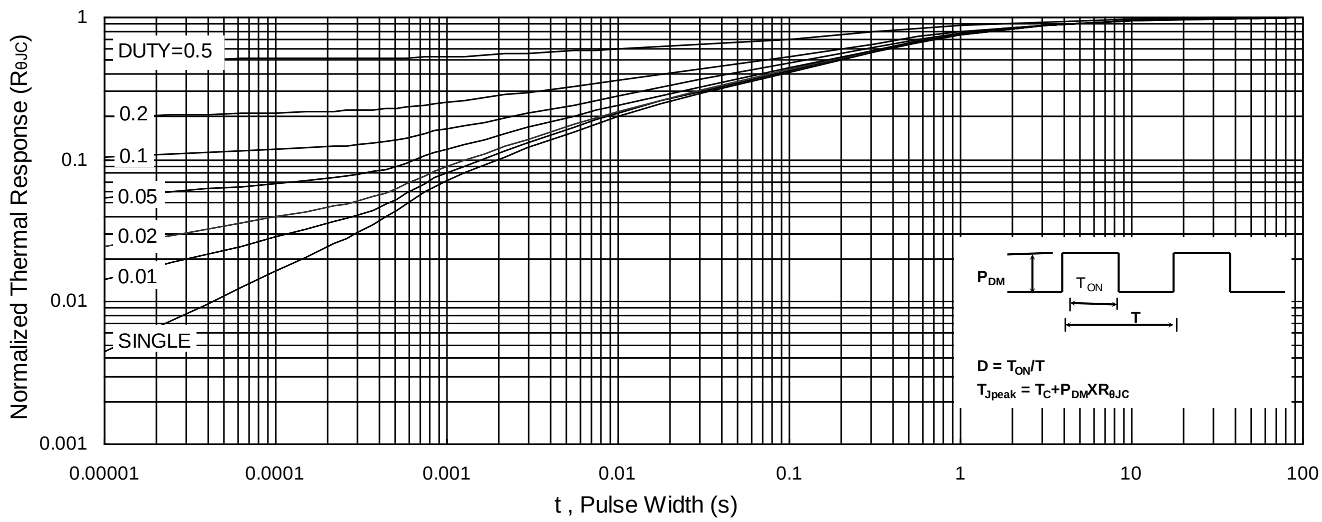


Fig.9 Normalized Maximum Transient Thermal Impedance

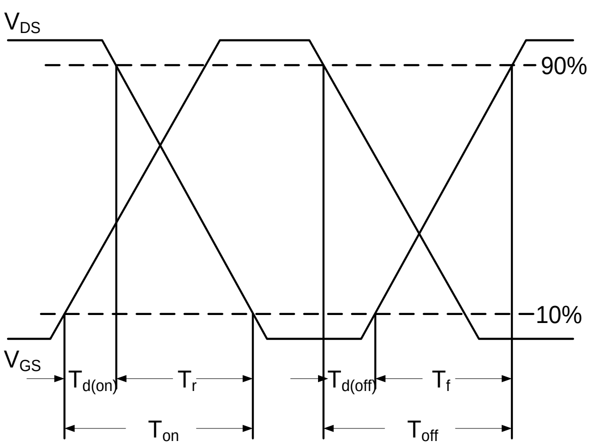


Fig.10 Switching Time Waveform

$$EAS = \frac{1}{2} L \times I_{AS}^{2} \times \frac{BV_{DSS}}{BV_{DSS} - V_{DD}}$$

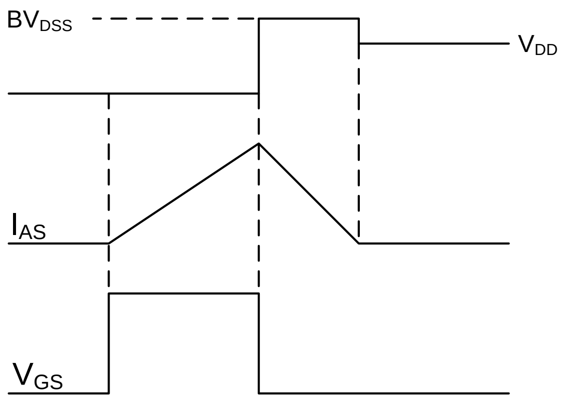


Fig.11 Unclamped Inductive Waveform

P-Channel Typical Characteristics

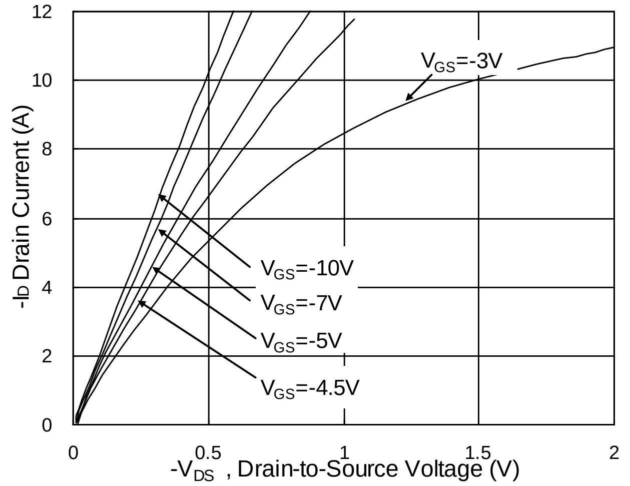


Fig.1 Typical Output Characteristics

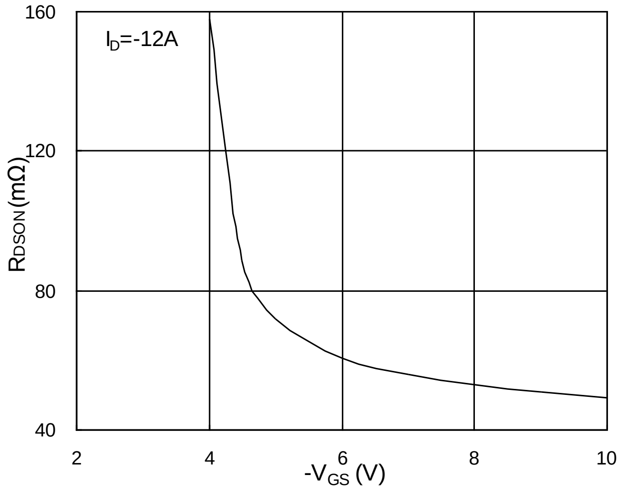


Fig.2 On-Resistance v.s Gate-Source

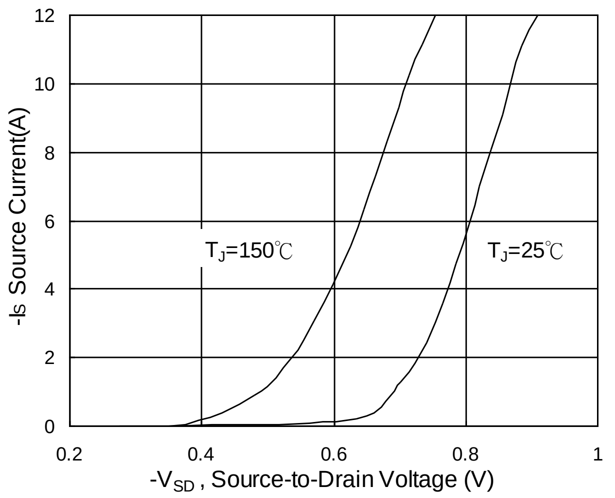


Fig.3 Forward Characteristics of Reverse

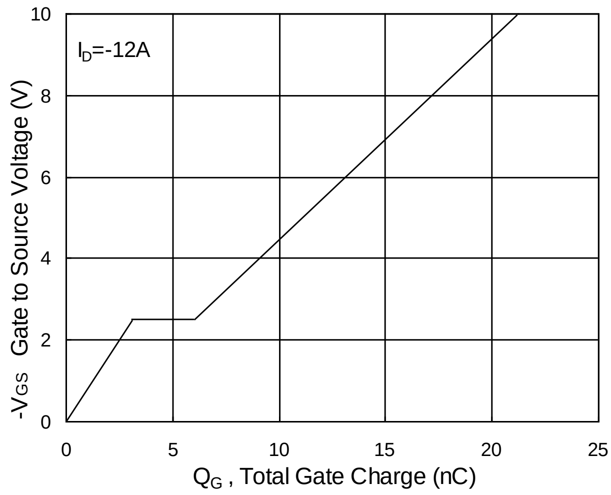


Fig.4 Gate-Charge Characteristics

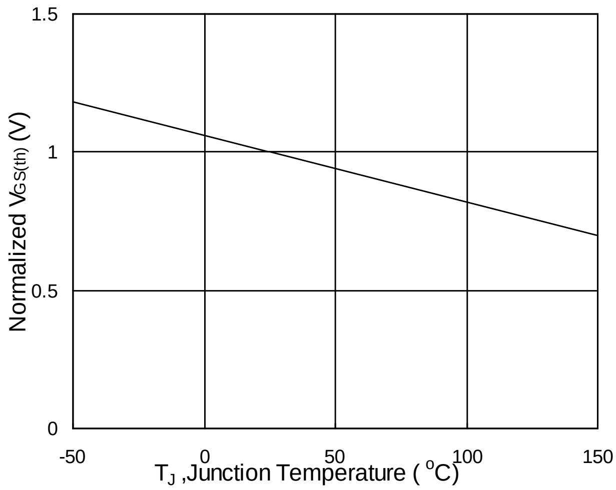


Fig.5 Normalized $V_{GS(th)}$ v.s T_J

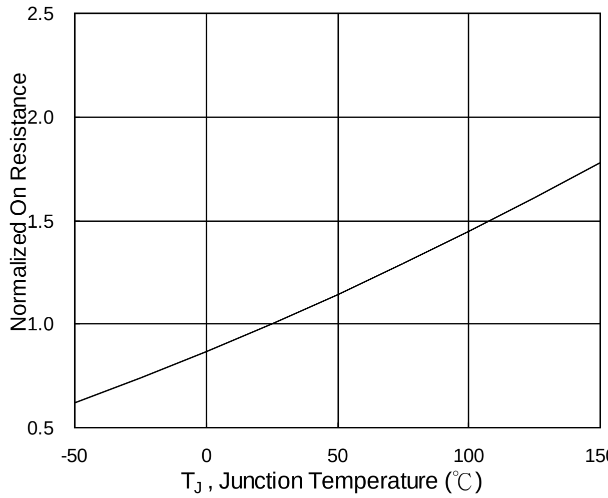


Fig.6 Normalized R_{DSON} v.s T_J

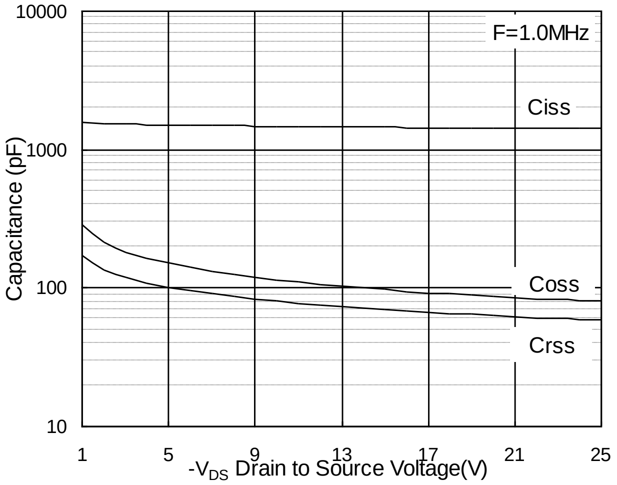


Fig.7 Capacitance

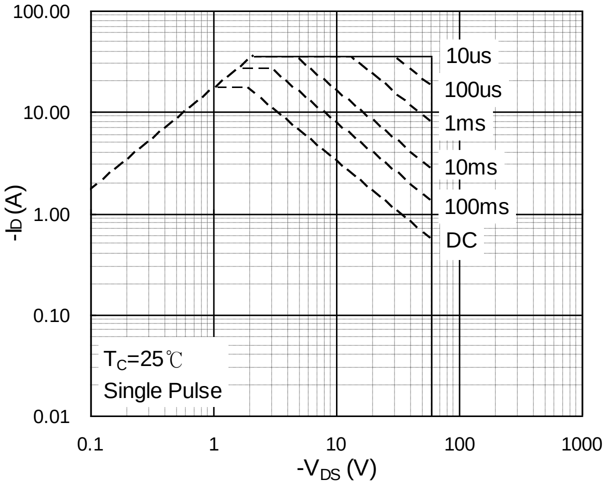


Fig.8 Safe Operating Area

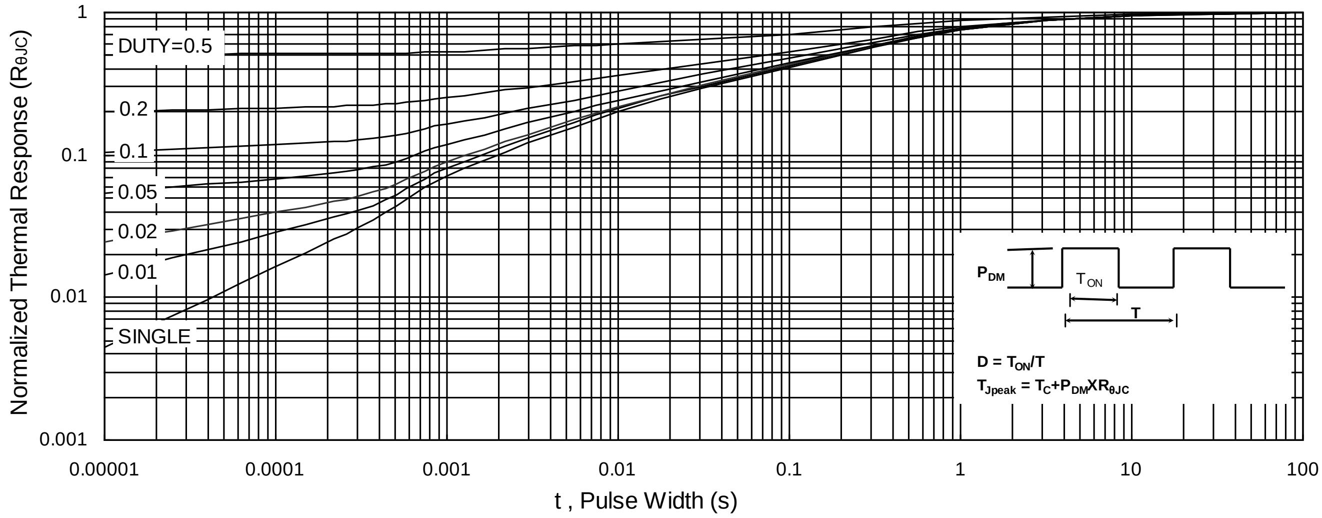


Fig.9 Normalized Maximum Transient Thermal Impedance

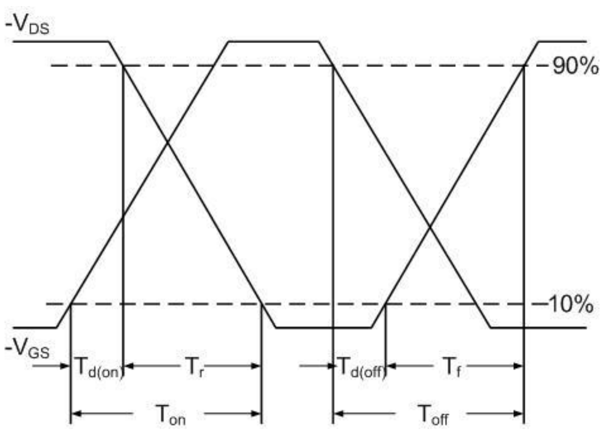


Fig.10 Switching Time Waveform

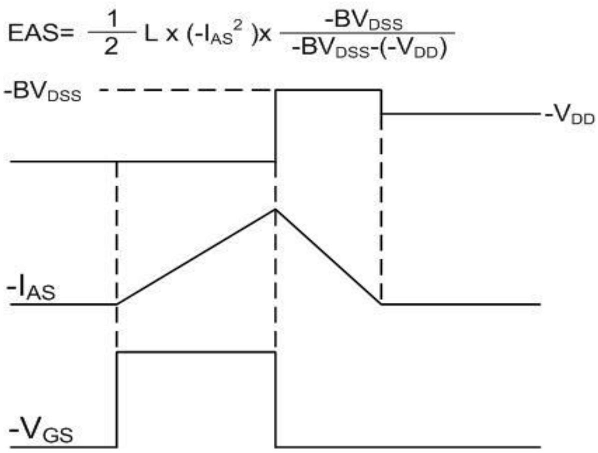
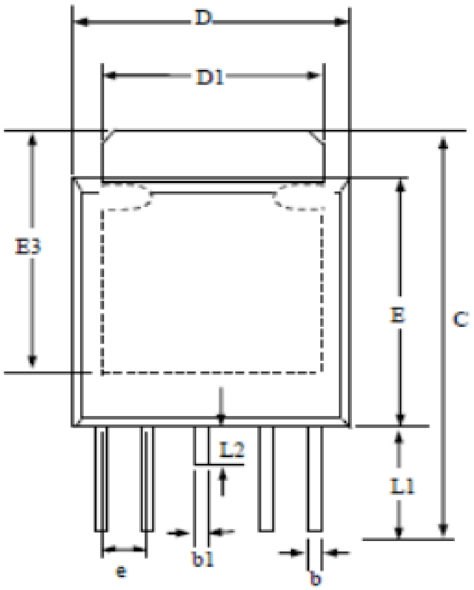


Fig.11 Unclamped Inductive Waveform

Package Mechanical Data

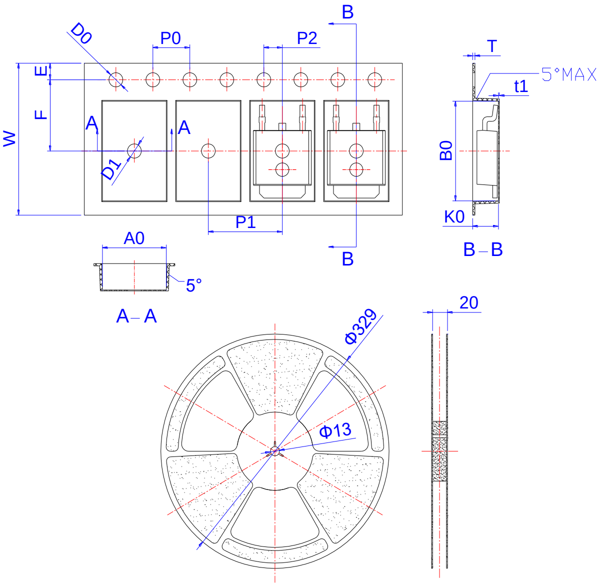


SYMBOLS	Millimeters		
	MIN	NOM	MAX
D	6.30	6.55	6.80
D1	4.80	5.35	5.90
C	9.30	9.75	10.20
E	5.30	5.80	6.30
E3	4.50	5.15	5.80
L	0.90	1.35	1.80
L1	2.00	2.53	3.05
L2	0.50	0.85	1.20
b	0.30	0.50	0.70
b1	0.40	0.60	0.80
A	2.10	2.30	2.50
A2	0.40	0.53	0.65
A1	0.00	0.10	0.20
e	1.20	1.30	1.40

1.All Dimensions Are in Millimeters.

2.Dimension Does Not Include Mold Protrusions.

Reel Specification-TO-252-4



Ref.	Dimensions					
	Millimeters			Inches		
	Min.	Typ.	Max.	Min.	Typ.	Max.
W	15.90	16.00	16.10	0.626	0.630	0.634
E	1.65	1.75	1.85	0.065	0.069	0.073
F	7.40	7.50	7.60	0.291	0.295	0.299
D0	1.40	1.50	1.60	0.055	0.059	0.063
D1	1.40	1.50	1.60	0.055	0.059	0.063
P0	3.90	4.00	4.10	0.154	0.157	0.161
P1	7.90	8.00	8.10	0.311	0.315	0.319
P2	1.90	2.00	2.10	0.075	0.079	0.083
A0	6.85	6.90	7.00	0.270	0.271	0.276
B0	10.45	10.50	10.60	0.411	0.413	0.417
K0	2.68	2.78	2.88	0.105	0.109	0.113
T	0.24		0.27	0.009		0.011
t1	0.10			0.004		
10P0	39.80	40.00	40.20	1.567	1.575	1.583

Flow (wave) soldering (solder dipping)

Product	Peak Temperature	Dipping Time
Pb device	245℃±5℃	5sec±1sec
Pb-Free device	260℃+0/-5℃	5sec±1sec

This integrated circuit can be damaged by ESD UniverChip Corporation recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedure can cause damage. ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

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